

FIG. 1

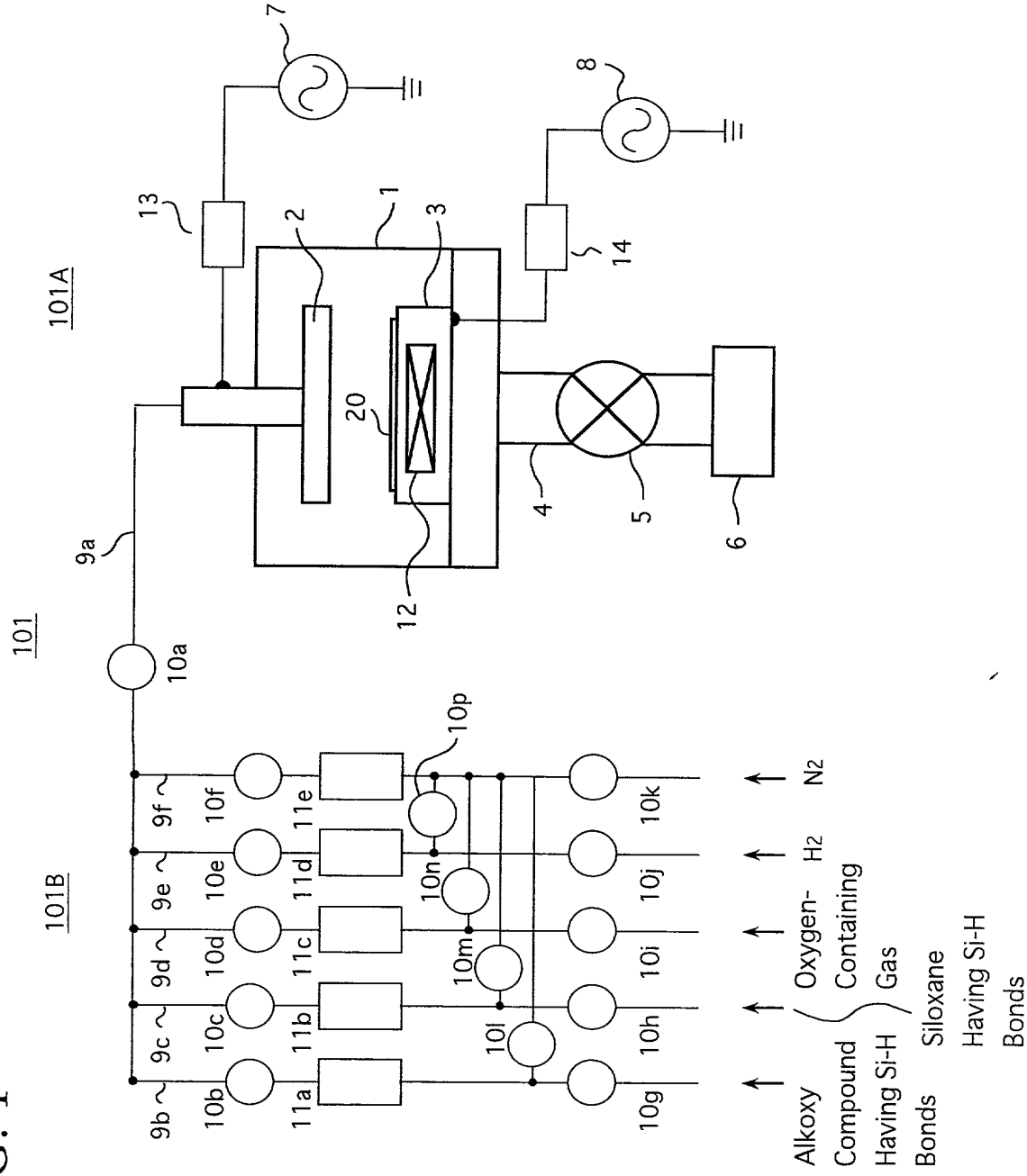


FIG. 2A

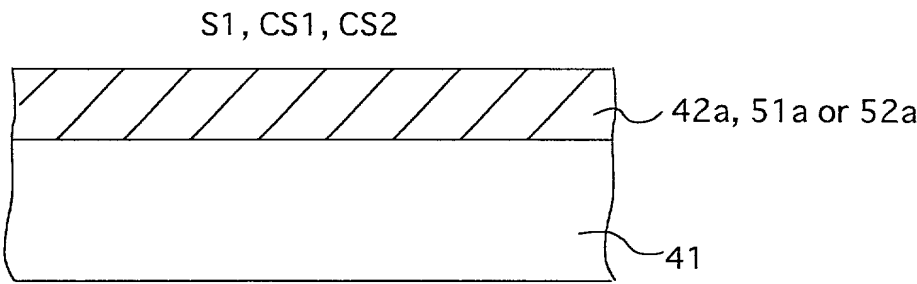


FIG. 2B

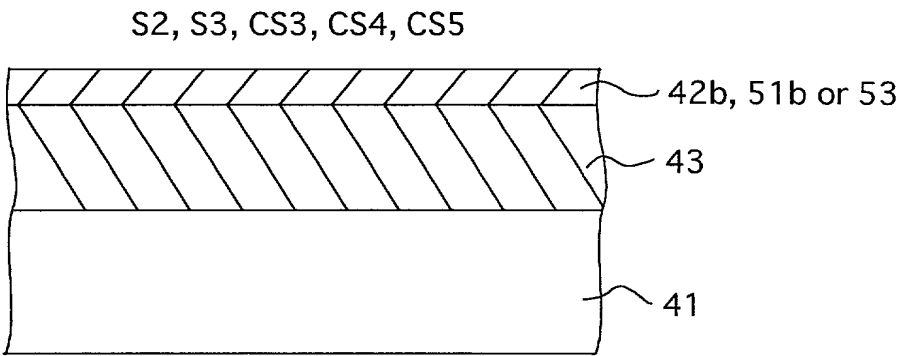


FIG. 2C

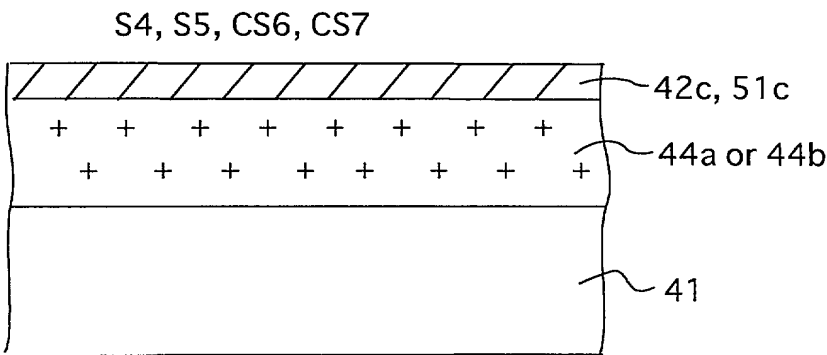


FIG. 2D

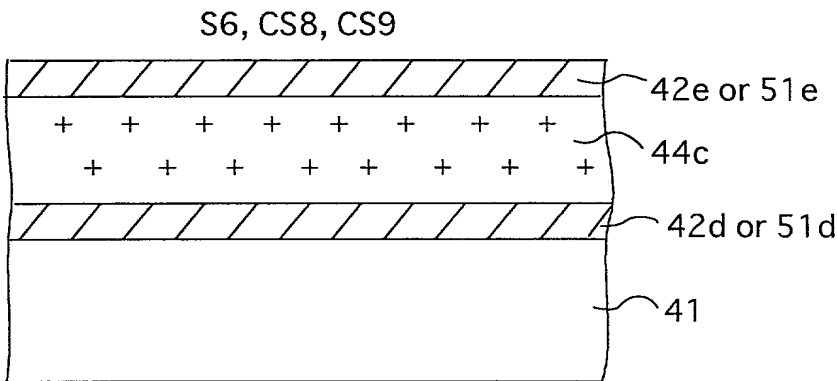


FIG. 2E

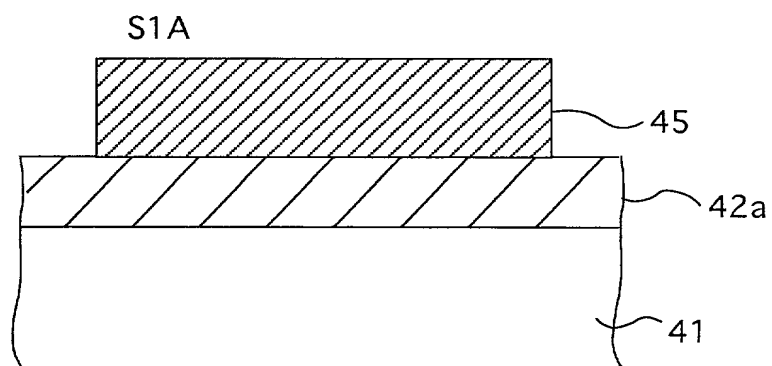


FIG. 3A

Film Density Measured by the X-Ray Interference Method

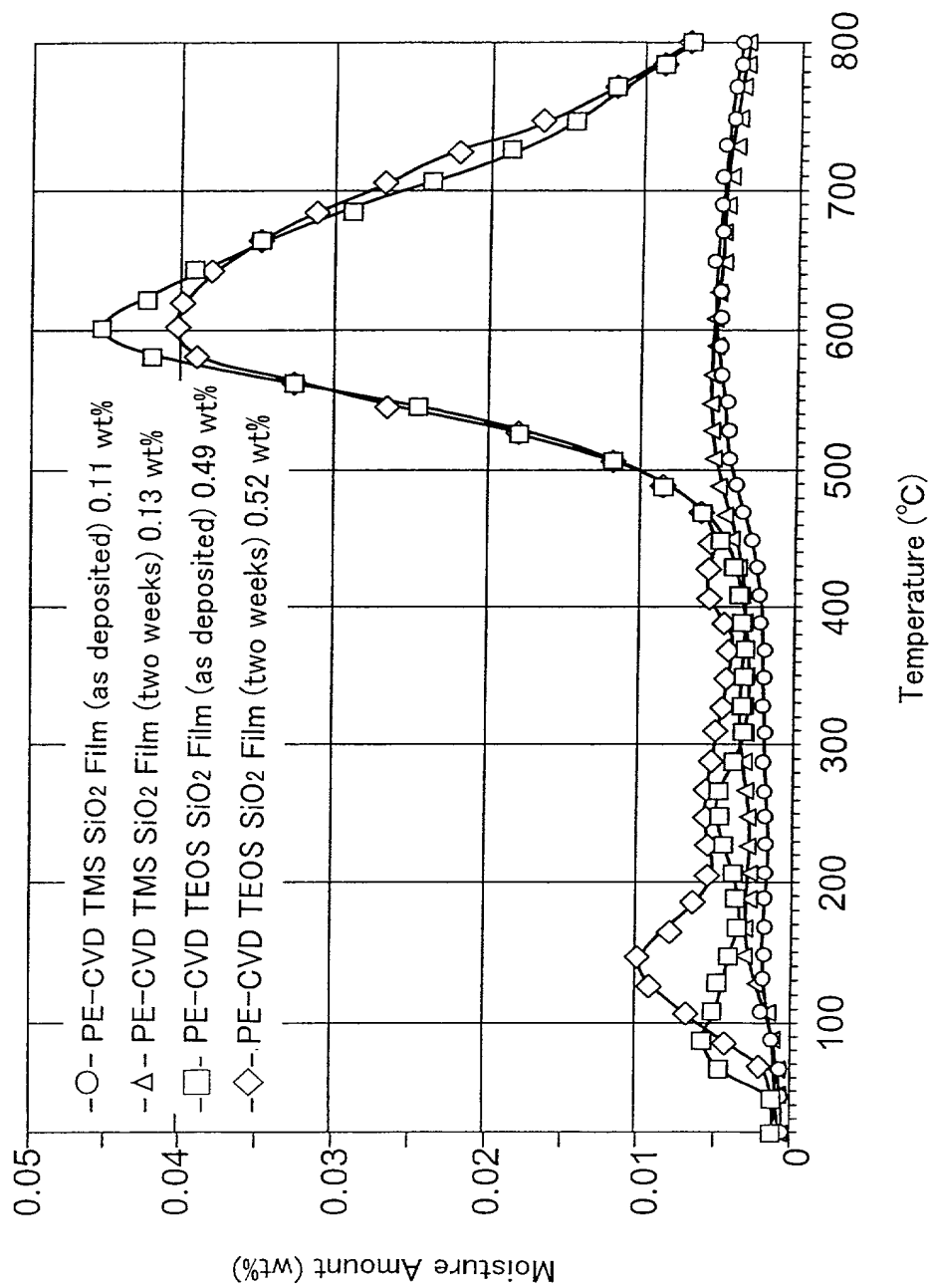
Examined Film Type	PE-CVD TMS SiO ₂ Film	PE-CVD TEOS SiO ₂ Film	PE-CVD SiH ₄ SiO ₂ Film	Thermal SiO ₂ Film
Film Density (g/cm ³)	2.33	2.26	2.24~2.30	2.23

FIG. 3B

Film Density Measured by the Weight Measurement

Examined Film Type	PE-CVD TMS SiO ₂ Film	PE-CVD TEOS SiO ₂ Film	PE-CVD SiH ₄ SiO ₂ Film
Film Density (g/cm ³)	2.33	2.1~2.2	2.20

FIG. 4



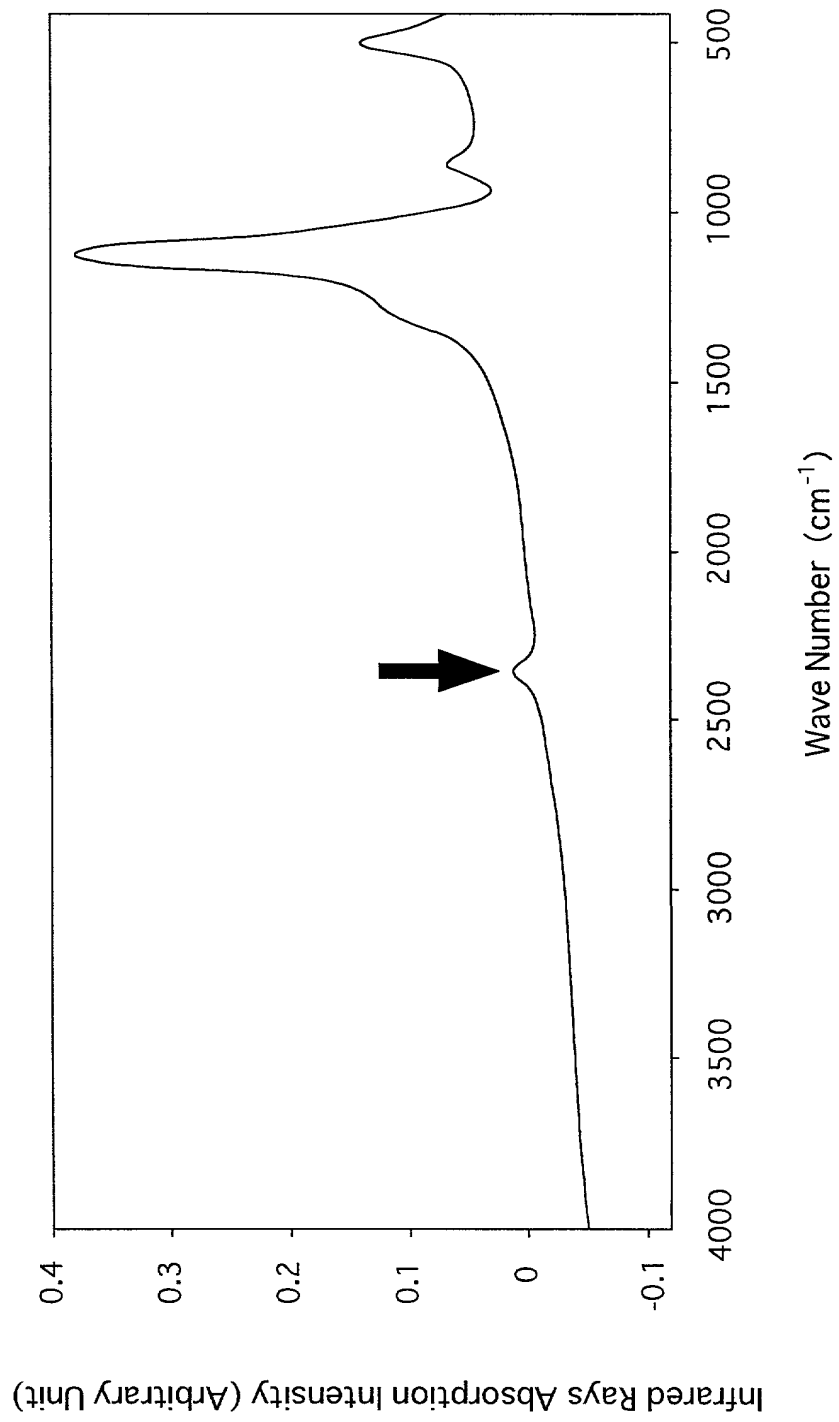


FIG. 5A

FIG. 5B

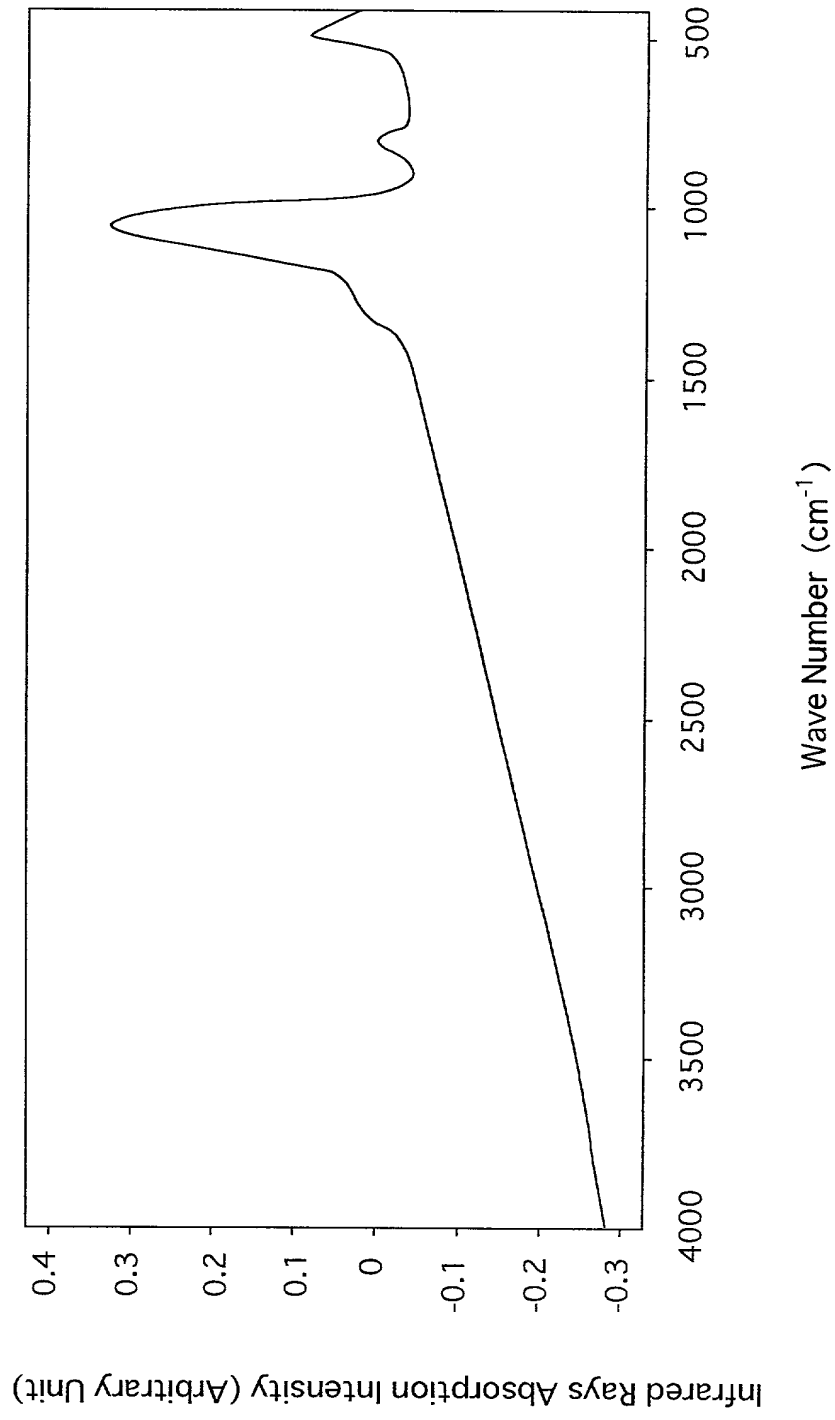


FIG. 6

Pressure Cooker Test

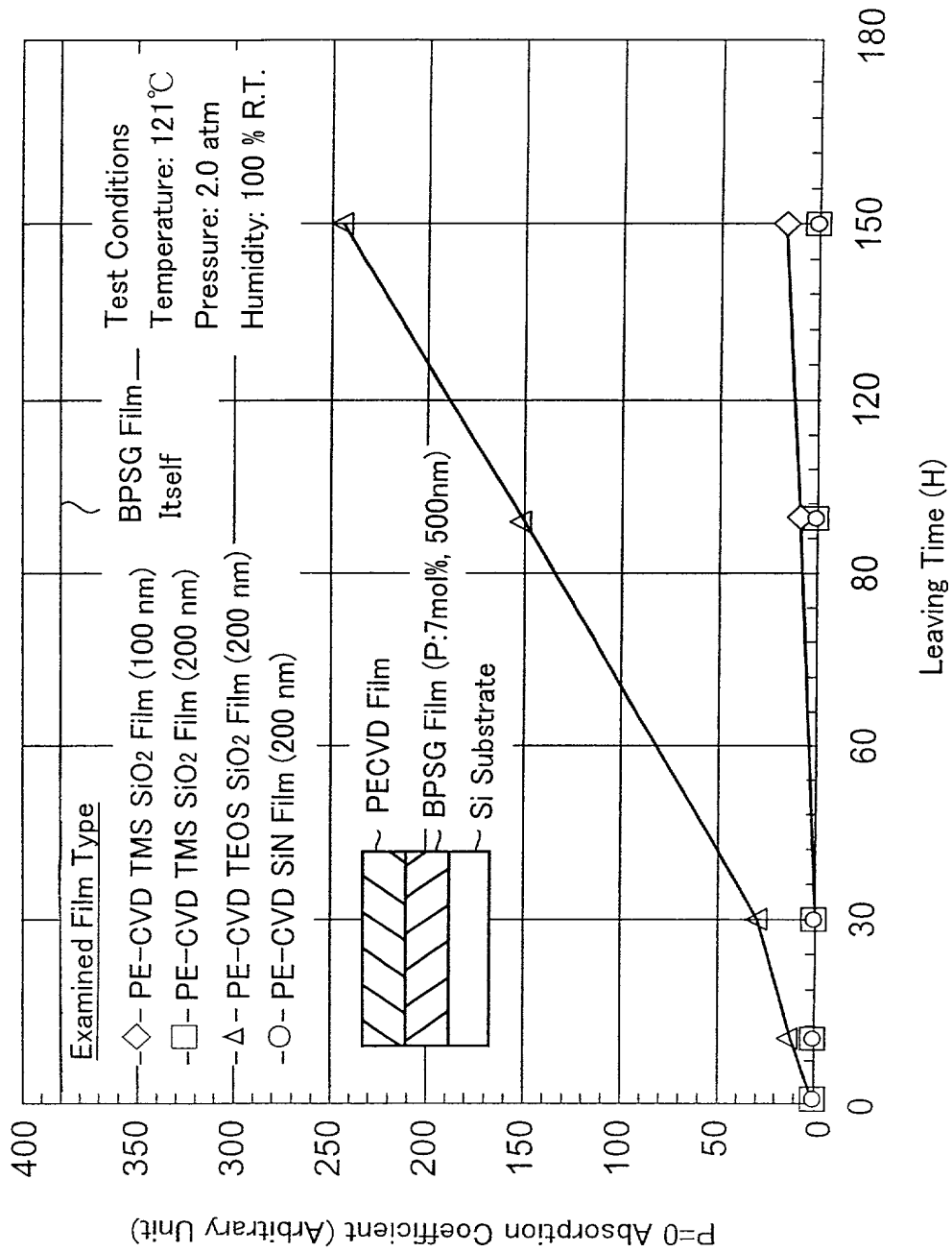


FIG. 7

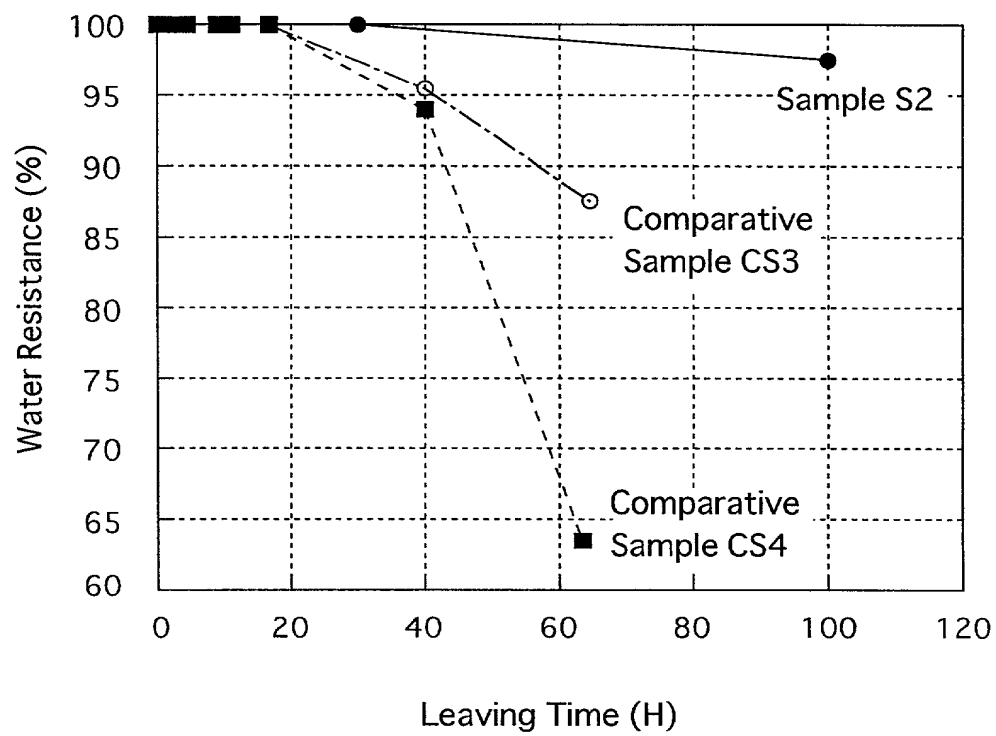


FIG. 8

Underlying Low Dielectric Constant Insulating Film Type	Surface Treatment	Examined Film Type	
		PE-CVD TMS SiO ₂ Film	PE-CVD TEOS SiO ₂ Film
Inorganic Coating Insulating Film k=2.9	Applied	○	△
	Not Applied	○	×
Organic Coating Insulating Film k=2.8	Applied	○	△
	Not Applied	○	×

FIG. 9

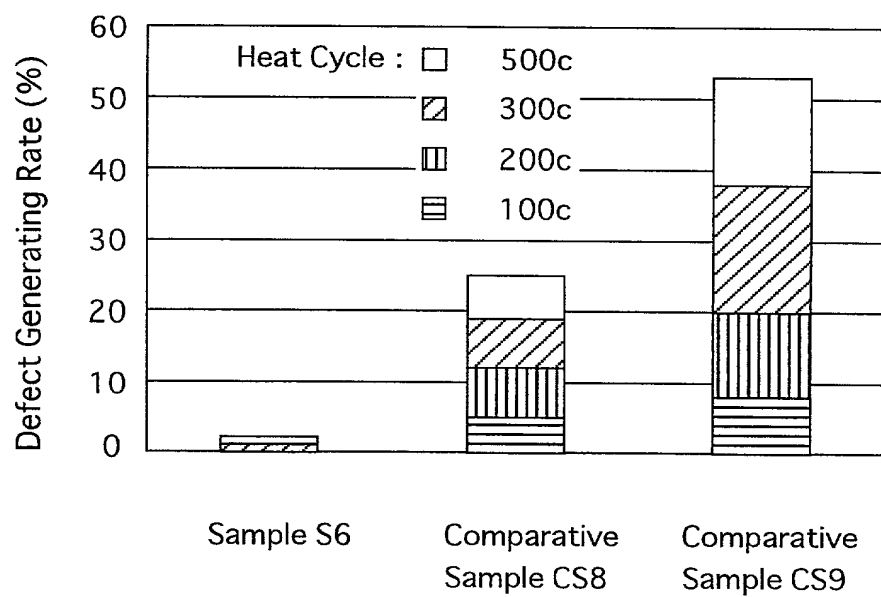


FIG. 10

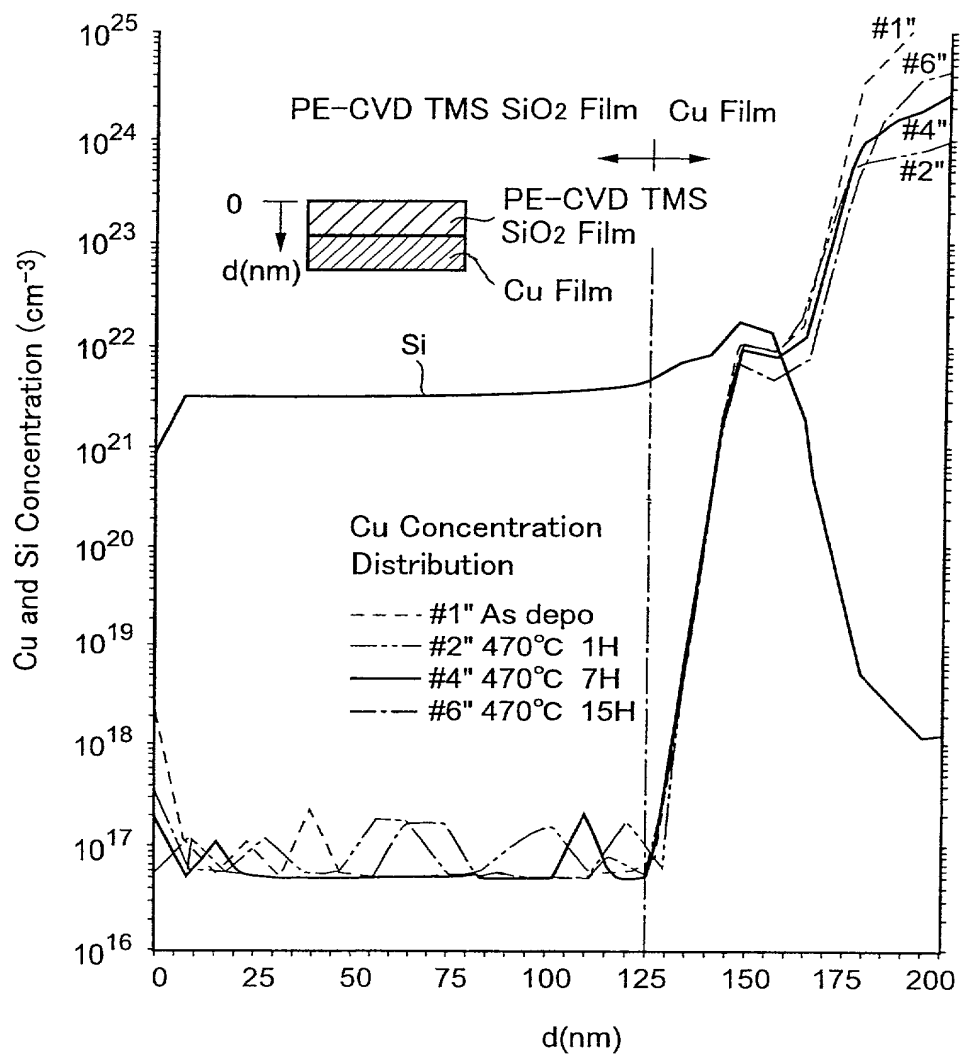


FIG. 11A

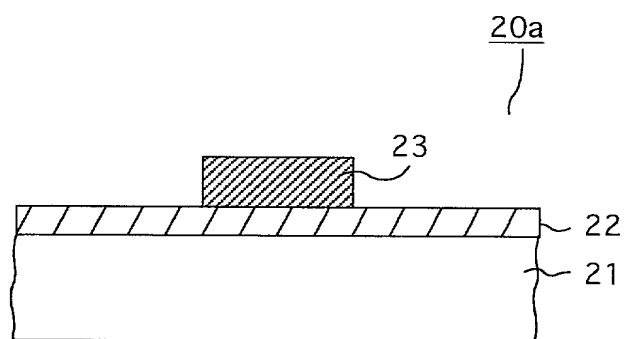


FIG. 11B

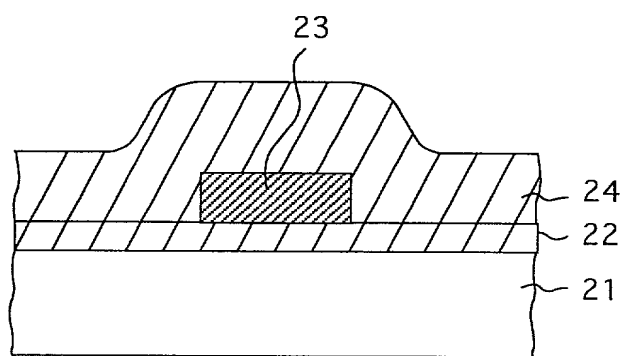


FIG. 12A

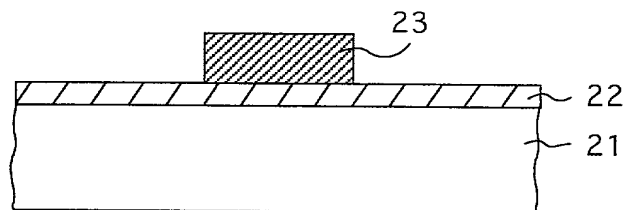


FIG. 12B

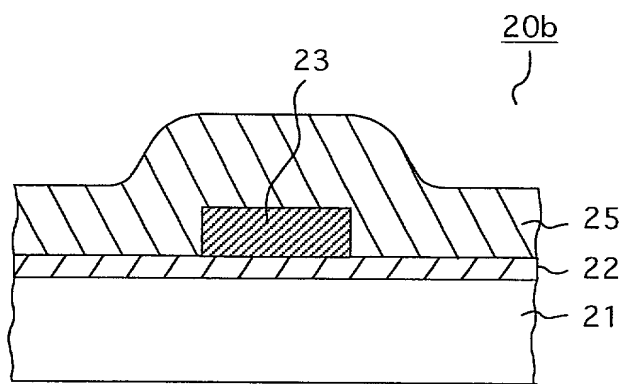


FIG. 12C

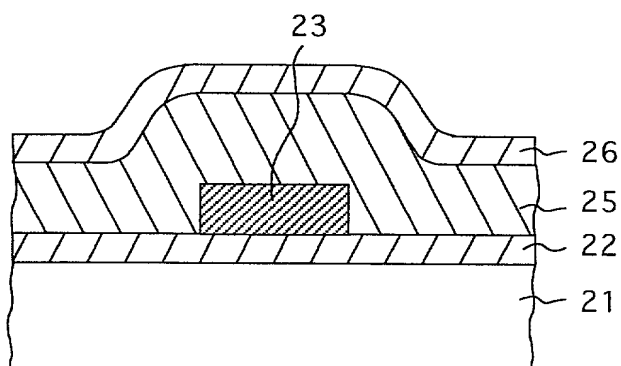


FIG. 13A

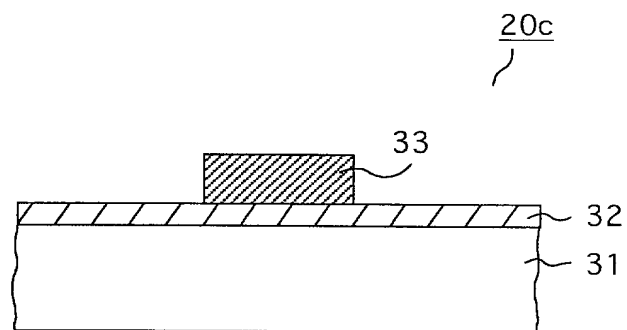


FIG. 13B

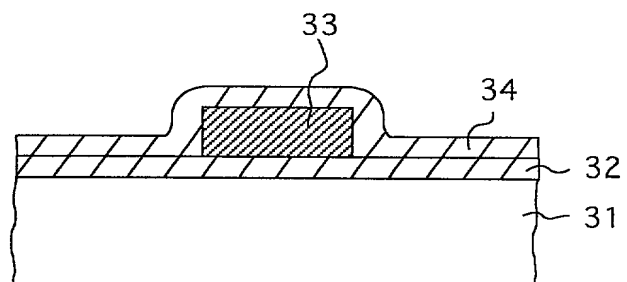


FIG. 13C

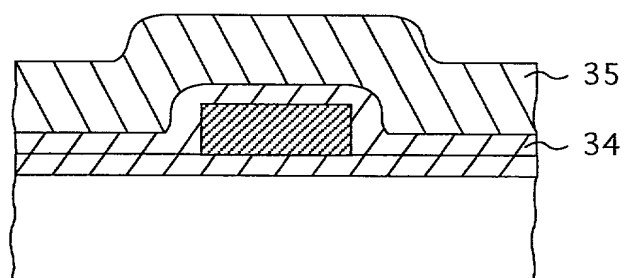


FIG. 13D

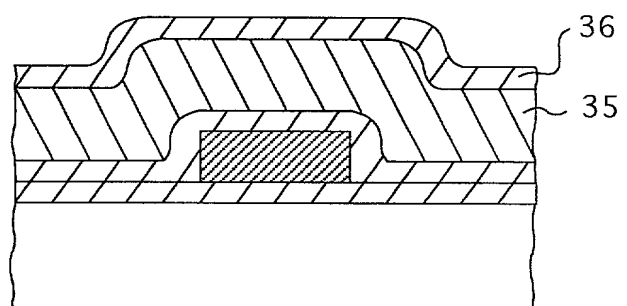


FIG. 13E

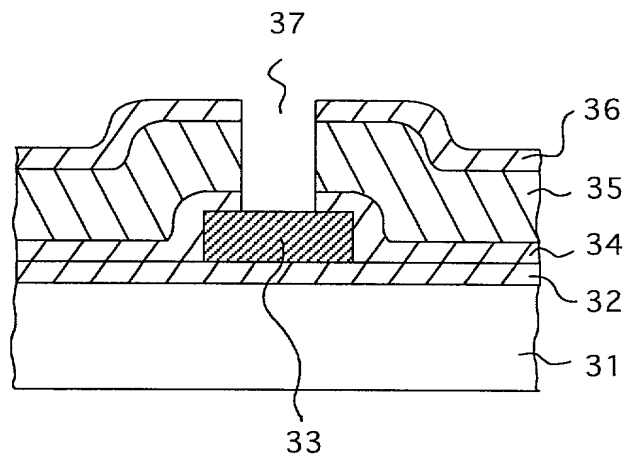


FIG. 13F

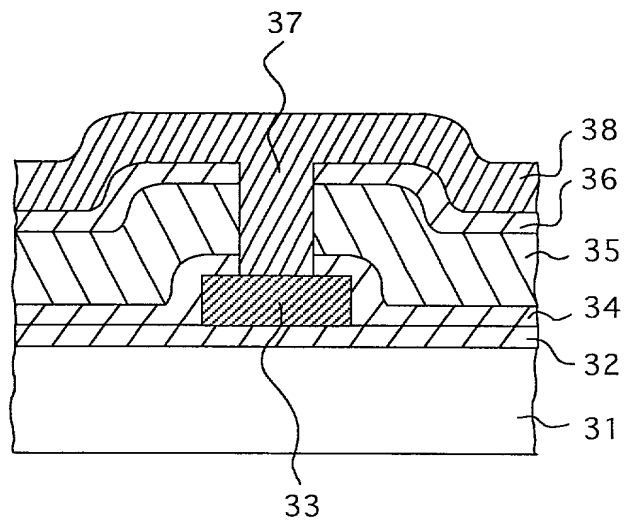


FIG. 14A

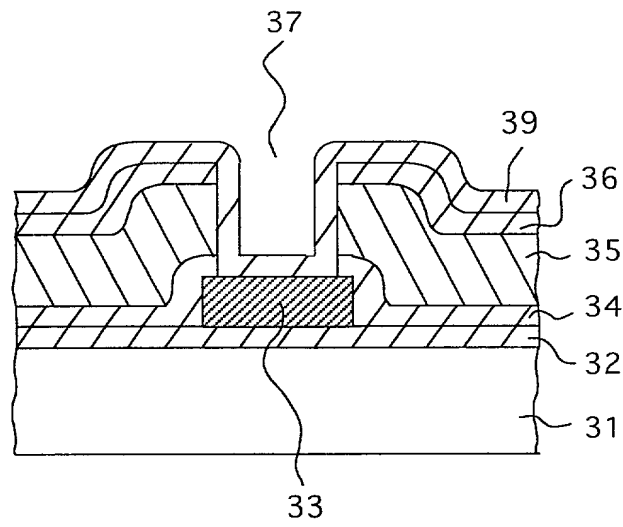


FIG. 14B

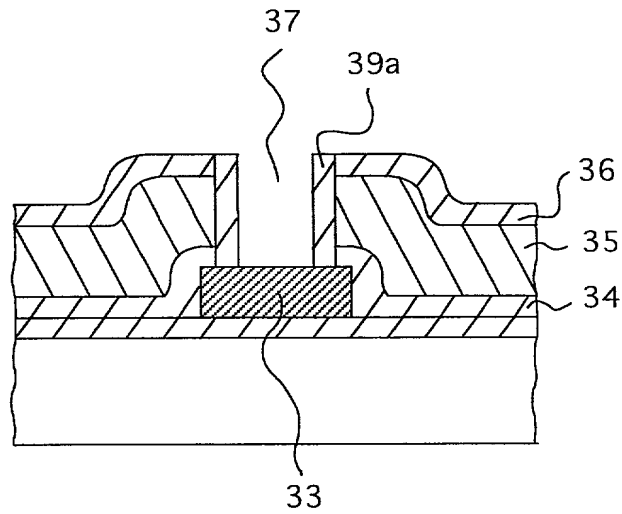


FIG. 14C

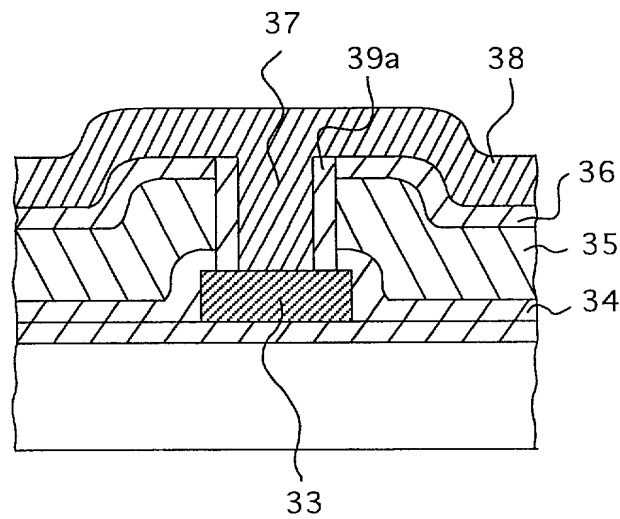


FIG. 15

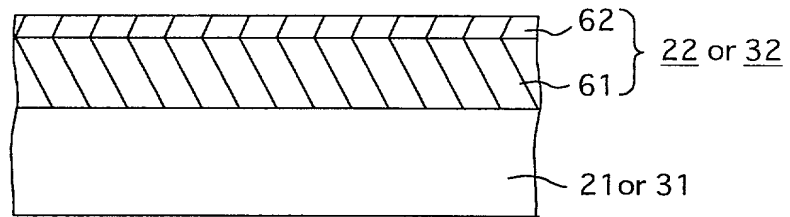


FIG. 16

